

ECE 340 - Semiconductor Electronics

Monday, 28 August 2017

22 nm scale currently \rightarrow harder to follow Moore's law \nearrow GDP 4% \rightarrow 2%

semiconductors - more flexible than conductors or insulators

device scaling

challenges: many, heating, etc.

tricks: More "Moore", Beyond Moore

unannounced quizzes

See course website.

Solid State Electronics Devices

Streetman & Banerjee, 7th.

$$J_p(x_n) \approx J_p(\text{diff.}) = -q D_p \frac{dp(x_n)}{dx_n} = q D_p \frac{\Delta p_n}{l}$$

$$I_p(x_n) = A J_p(\text{diff.}) = q A \frac{D_p}{l} p_n (e^{qV/kT} - 1)$$

(= Δ?)

$$I_n(\text{recomb.}) = \frac{Q_p}{\tau_p} = \frac{\frac{1}{2} q A l \Delta p_n}{\tau_p}$$

space-charge neutrality

$$= \frac{q A l}{2 \tau_p} p_n (e^{qV/kT} - 1)$$

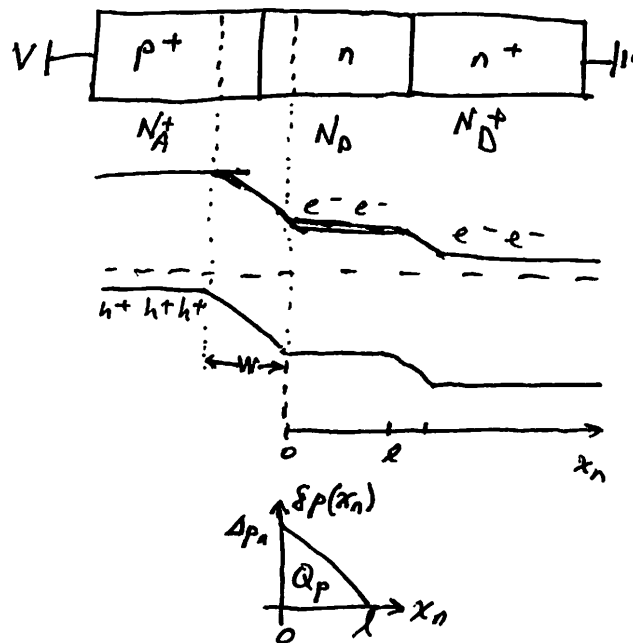
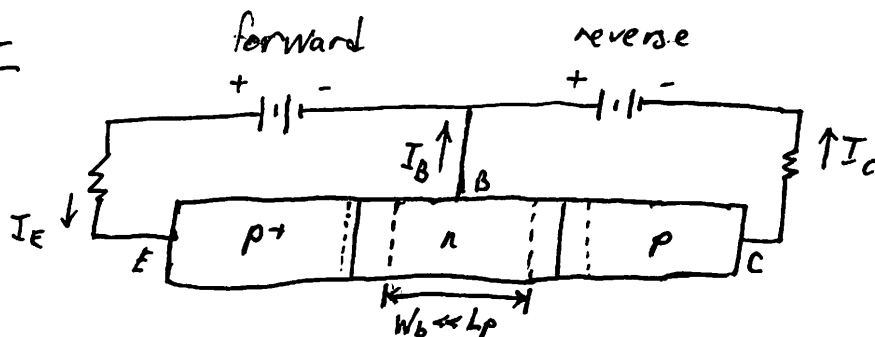
$$I_n(\text{recomb.}) = I_p(x_n=0) - I_p(x_n=l)$$

$$= I_p(x_n=0) \left[\frac{l^2}{2L_p^2} \right]$$

$$I_p(x_n=0) = q A \frac{D_p}{L_p} \Delta p_n \coth n \left(\frac{l}{L_p} \right)$$

$$= q A \frac{D_p}{L_p} \Delta p_n \left[\frac{L_p}{l} + \frac{l}{3L_p} \right] = q A \frac{D_p}{l} \Delta p_n \frac{l}{L_p} \left[\frac{L_p}{l} + \frac{l}{3L_p} \right] = q A \frac{D_p}{l} \Delta p_n \left[1 + \frac{l^2}{3L_p^2} \right]$$

$$I_n(\text{inj.}) = q A \frac{D_p}{L_n} n_p (e^{qV/kT} - 1)$$

BJT

$$I_E = I_B + I_C$$

$$V_{BE} > 0$$

$$V_{CB} < 0$$

$$I_{Ep} = \gamma I_E$$

$$\gamma = \frac{I_{Ep}}{I_{Ep} + I_{En}}$$

γ emitter injection efficiency

$$I_{Cp} = B I_{Ep} = B \gamma I_E$$

B base transport factor

$$\approx \alpha I_E$$

α current transfer ratio

$$\beta = \left(\frac{I_C}{I_B(\text{normal mode})} \right) = \frac{\alpha}{1-\alpha}$$

$$- \frac{d \delta p(x_n)}{dx_n} = \frac{\Delta p_E - \Delta p_C}{W_b}$$

neglect for normal mode

$$I_C = q A \frac{D_p}{W_b} \Delta p_E = q A \frac{D_p}{W_b} p_n (e^{qV_{EB}/kT} - 1)$$

$$I_E = I_{E_p} + I_{E_n}$$

$$= qA \left[\frac{D_p}{N_b} p_n + \frac{D_n^E}{L_n^E} n_p^E \right] (e^{qV_{EB}/kT} - 1)$$

$$\beta = \left[1 + \frac{I_{En}}{I_{Ep}} \right]^{-1} \approx \left[1 + \frac{D_n^E}{L_n^E} \frac{W_b}{D_p} \frac{n_p^E}{p_n} \right]^{-1} \approx \frac{1}{1 + \frac{\mu_n^E}{\mu_p^B} \frac{W_b}{L_n^E} \frac{N_D^B}{N_A^E}}$$

$$Q_p = qA \frac{1}{2} W_b (\Delta p_E + \Delta p_C)$$

neglect for normal mode. Why?

$$I_B (\text{recomb.}) = \frac{Q_p}{\tau_p} \approx \frac{qAW_b}{2\tau_p} p_n (e^{qV_{EB}/kT} - 1)$$

$$I_B (\text{inj.}) = I_{En} = \frac{qAD_n^E}{L_n^E} n_p^E (e^{qV_{EB}/kT} - 1)$$

$$I_B = I_B (\text{recomb.}) + I_B (\text{inj.})$$

$$\beta \gg 1 = \frac{I_C}{I_B (\text{recomb.})} = \frac{B}{1-B} = \frac{\frac{qAD_p}{W_b} \Delta p_E}{\frac{qAW_b}{2\tau_p} \Delta p_E} = \frac{2L_p^2}{W_b^2} \quad \text{for } W_b \ll L_p$$

$$L_p = \sqrt{D_p \tau_p}$$

$$B \approx 1 - \frac{1}{2} \left(\frac{W_b}{L_p} \right)^2 \quad \text{for } W_b \ll L_p$$

$$Q_p = I_B (\text{recomb.}) \tau_p$$

$$I_C = \frac{Q_p}{\tau_t} \quad \text{transit time } \tau_t \ll \tau_p \quad \text{"ideal" transistor}$$

$$\beta \gg 1 = \frac{I_C}{I_B (\text{recomb.})} = \frac{\tau_p}{\tau_t} \gg 1$$

$$\approx \frac{2L_p^2}{W_b^2}$$

$$\Rightarrow \tau_t = \frac{W_b^2}{2D_p}$$

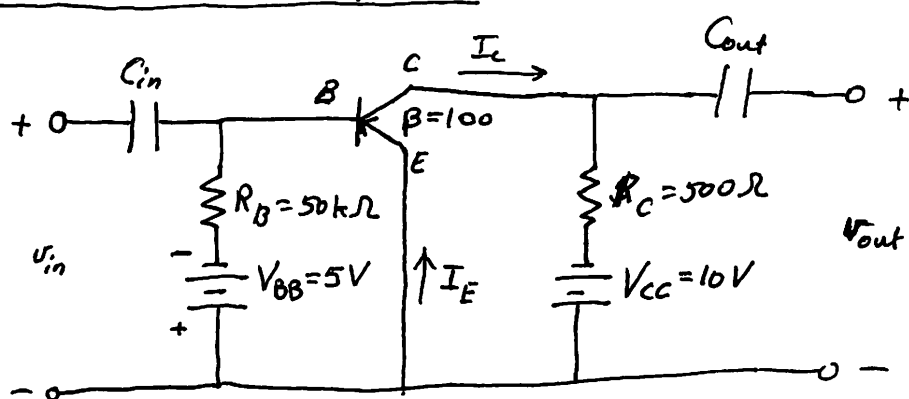
Common-Emitter Amplifier

Fig. 7-4

$$I_E = I_B + I_C$$

DC bias levels

emitter junction forward biased $V_{EB} > 0$

collector junction reverse biased $V_{CB} < 0$

$$I_C = \beta I_B \approx I_{ES} (e^{qV_{EB}/kT} - 1)$$

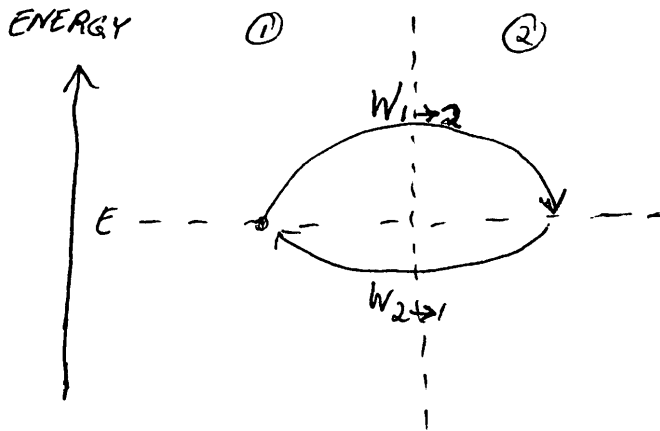
$$I_{ES} \approx qA \left(\frac{D_p}{W_b} p_n + \frac{D_n}{L_n} n_p \right)$$

saturated

$$V_{BB} = V_{EB} + I_B R_B$$

$$I_B = \frac{V_{BB} - V_{EB}}{R_B}$$



Fermi Level Invariance at Equilibrium (T)

$W_{1 \rightarrow 2}$ (RATE/cm³): # of ELECTRONS
TRANSFERRING FROM
① to ② / s / UNIT VOLUME
 $W_{2 \rightarrow 1}$
② to ①

At equilibrium,

$$W_{1 \rightarrow 2} = W_{2 \rightarrow 1}$$

$$W_{1 \rightarrow 2} \propto \underbrace{N_1(E) f_1(E)}_{\text{\# of } e^- \text{ at } E \text{ in } ①} \underbrace{N_2(E) [1 - f_2(E)]}_{\text{\# of empty states at } E \text{ in } ②}$$

$$\parallel$$

$$W_{2 \rightarrow 1} \propto \underbrace{N_2(E) f_2(E)}_{\text{\# of } e^- \text{ at } E \text{ in } ②} \underbrace{N_1(E) [1 - f_1(E)]}_{\text{\# of empty states at } E \text{ in } ①}$$

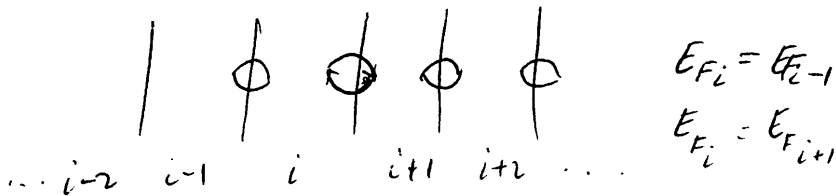
From $W_{1 \rightarrow 2} = W_{2 \rightarrow 1}$: $f_1(E) [1 - f_2(E)] = f_2(E) [1 - f_1(E)]$

$$f_1(E) = f_2(E)$$

$$\frac{1}{1 + \exp\left(\frac{E - E_{F1}}{kT}\right)} = \frac{1}{1 + \exp\left(\frac{E - E_{F2}}{kT}\right)}$$

$$\Rightarrow E_{F1} = E_{F2} \text{ IFF } T_1 = T_2 = T$$

GENERALIZATION: SYSTEM PARTITION



EQUILIBRIUM \leftrightarrow CONSTANT FERMİ LEVEL

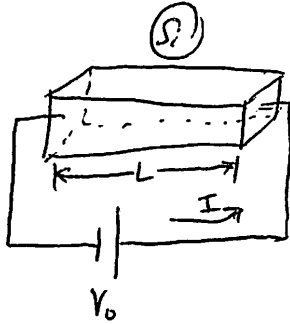
DRIFT (\vec{E}) $\Rightarrow \vec{V}_d = \mu \vec{E}$

\uparrow
 Mobility
 $(\text{cm}^2/\text{V-s})$

$\mu = \frac{q}{m^*} \tau$

\uparrow
 (scattering time)
 effective mass

$\vec{J}_m = q n_0 \vec{V}_d$ $I_m = J_m A$



If $N_d = 10^{17} / \text{cm}^3 \Rightarrow (T=300 \text{ K}) n_0 = 10^{17} / \text{cm}^3$

$\mathcal{E} = \frac{V_0}{L} = \frac{1}{10^{-3}} = 1 \text{ kV/cm}$

$\mu_n(N_d = 10^{17} / \text{cm}^3) = 1000 \text{ cm}^2/\text{V-s}$

$J_m = 1.6 \times 10^{-19} \times 10^{17} \times 10^3 \times 10^3 = \underline{1.6 \times 10^4 \text{ A/cm}^2}$

Chapter 4

semiconductors - doping, temperature, light effects

Excess carriers in semiconductors

creation of carriers in excess of the thermal equilibrium values

⇒ device operation

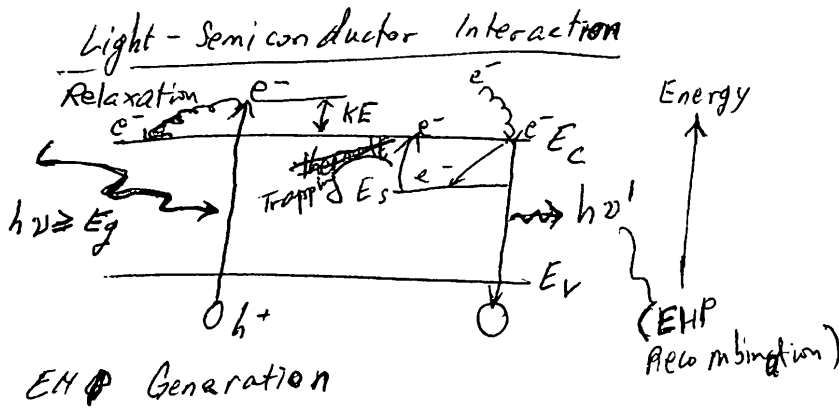
Because excess carriers dominate the conduction process in semiconductor materials

Several ways of creation of Excess carriers:

- optical absorption
- electron bombardment
- inject across a p-n junction

Optical absorption {

- photoconductive properties
- EHP Recombination
- carrier trapping



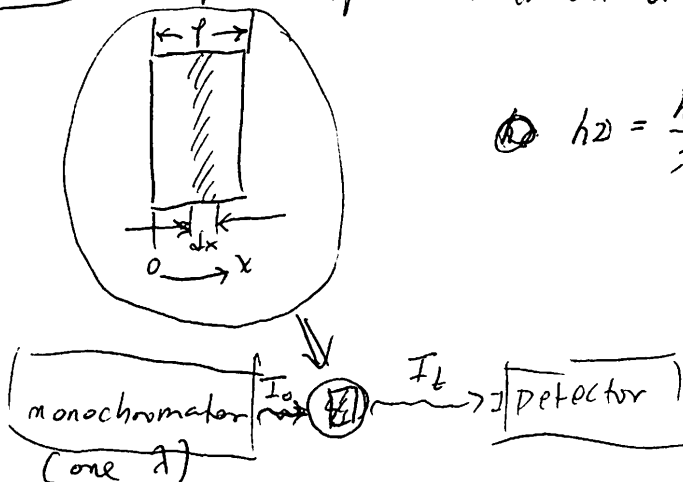
Relaxation - similar to a car slowing down w/o gas due to friction collisions w/ lattice etc.

$$\nu' < \nu$$

Trapping - e^- re-emitted due to thermal energy

E_s - local defect e^- cannot move

Absorption Law: Optical Properties of Semiconductor



$$h\nu = \frac{hc}{\lambda} \quad \text{speed of light}$$

Between x and $x+dx$

$$dI = -\alpha(\lambda) I(x) dx$$

$$\left\{ \frac{dI}{dx} = -\alpha(\lambda) I(x) \right\}$$

Proportionality coefficient

$\alpha(\lambda)$: independent of x But depends on: Wavelength, Temperature, Material

Figure 4.2 Optical Absorption Experiment

Solution:
$$\begin{cases} I(x) = I_0 e^{-\alpha(\lambda)x} \\ I_t = I_0 e^{-\alpha(\lambda)l} \end{cases}$$

l : sample thickness

$\alpha(\lambda)$: absorption coefficient (cm^{-1})

$$\alpha(\lambda) = \frac{1}{l} \ln \frac{I_0}{I_t}$$

α negative - gain - laser

Wavelength dependence of α

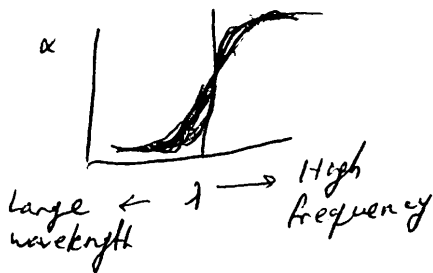


Fig 4-3

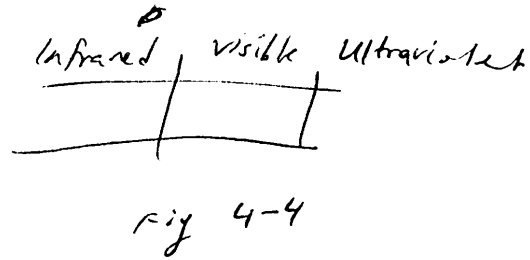


Fig 4-4

Luminescence (not incandescence (heated materials)) (e.g., LEDs)

Light emission resulting from a return to equilibrium

\sim opposite to absorption

According to the excitation mechanism:

- photoluminescence \leftarrow photon absorption
- cathode luminescence \leftarrow high-energy electron
- Electroluminescence \leftarrow current flowing through the sample

relaxation
order: picoseconds
photoluminescence:
nanoseconds

1) Photoluminescence

2) Phosphorescence: slow process (phosphors)

a) e⁻ excitation: EHP creation

b) Relaxation (lattice scattering): heat

c) trapping (delay)

ECE 340 Mon 23 Oct Lecture - Leburton

(a)

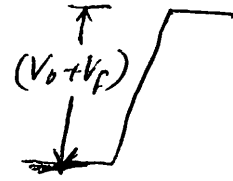
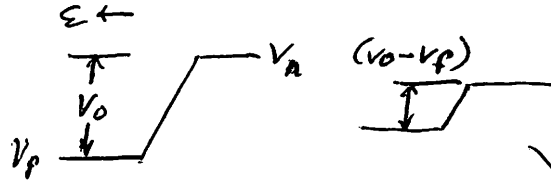
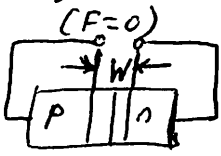
(b)

(c)

Equilibrium

Forward bias

Reverse bias



Particle Flow Current

→	→	Hole diffusion
←	←	Hole drift
←	→	Electron diffusion
→	←	Electron drift

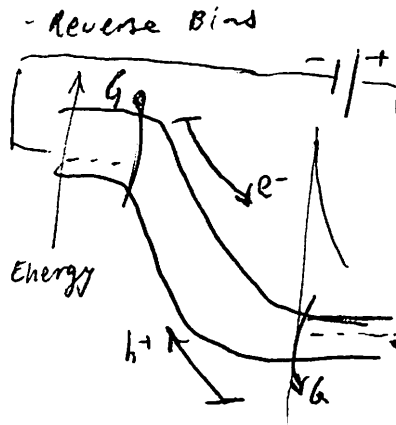
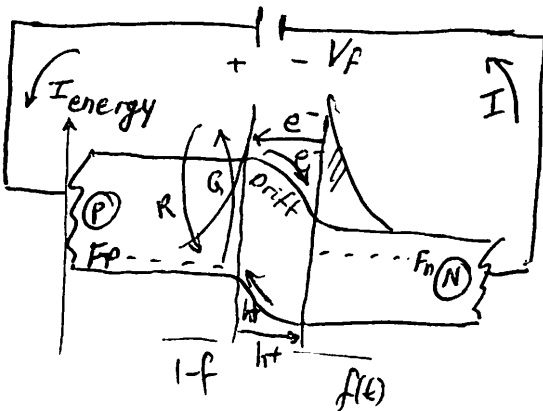
Carrier Injection (Forward Bias)

Particle Flow Current

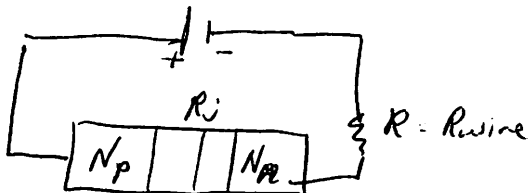
→	←
←	→
→	←
←	→

Particle Flow Current

→	→
←	←
→	→
←	←



(L.L.I.) - Low Level Injection : $n, p \ll N_A, N_D$



$$V_f = R I + \left(\frac{R}{N_n} + \frac{R}{N_p} + R_j \right) I$$

Carrier Injection: (Forward-Reverse-Biased Junctions)

FROM $V_0 = \frac{kT}{q} \ln \frac{P_p}{P_n} = \frac{kT}{q} \ln \frac{n_n}{n_p}$

$$\left[\frac{P_p}{P_n} = \frac{n_n}{n_p} = e^{\frac{qV_0}{kT}} \right]$$

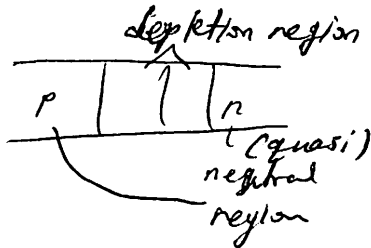
Non-Equilibrium: Low-level injection

~~Not a good approximation~~

So Neutral Region length $\gg L_{\{n\}}$ $\left\{ \begin{array}{l} \Rightarrow \text{excess carriers} \\ \text{will recombine entirely} \\ \text{in the neutral region} \end{array} \right.$

$$\delta p(x_n) = \Delta p(x_{n0}) = e^{-x_n/L_p}$$

$$\delta n(x_p) = \Delta p(-x_{p0}) = e^{-x_p/L_n}$$



Current

$$I_p = -q A D_p \frac{d\delta p}{dx_n} = q A \frac{D_p}{L_p} P_n \left(e^{\frac{qV}{kT}} - 1 \right) e^{-x_n/L_p}$$

$$I_n = q A D_n \frac{d\delta n}{dx_p} = -q A \frac{D_n}{L_n} n_p \left(e^{\frac{qV}{kT}} - 1 \right) e^{-x_p/L_n}$$

$$I = I_0 \left(e^{\frac{qV}{kT}} - 1 \right)$$

saturation current flat as a function of the bias

$$n_p = \frac{n_i^2}{N_A}$$

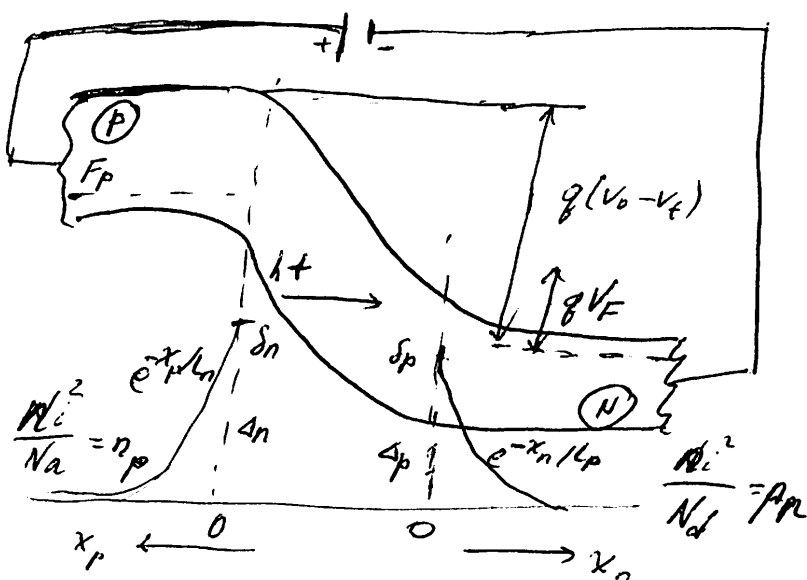
$$p_n = \frac{n_i^2}{N_D}$$

$$p_n = \frac{n_i^2}{N_D} \quad n_p = \frac{n_i^2}{N_A}$$

$p^+ - n$: If $N_A \gg N_D \Rightarrow p_n \gg n_p$

$p - n^+$: $\ll \ll$

Carrier Injection (Forward Bias)



$$\delta p(x_n) = \delta p e^{-x_n/L_p}$$

Area under curve

$$Q_p = qA \int_0^{\infty} dx_n \delta p(x_n)$$

$$Q_n = qA \delta n L_n$$

stored charge in n-side
minority carrier

$$= qA \delta p L_p$$

$$\frac{Q_n}{\tau_n}$$

$$\frac{Q_p}{\tau_p}$$

recombination current

Total current:

$$\frac{Q_n}{\tau_n} + \frac{Q_p}{\tau_p}$$

of injected carriers that are recombined.

$$\Delta n = n_p \left(e^{\frac{qV_F}{kT}} - 1 \right) = \frac{n_i^2}{N_A} \left(e^{\frac{qV_F}{kT}} - 1 \right)$$

$$\Delta p = p_n \left(e^{\frac{qV_F}{kT}} - 1 \right) = \frac{n_i^2}{N_D} \left(e^{\frac{qV_F}{kT}} - 1 \right)$$

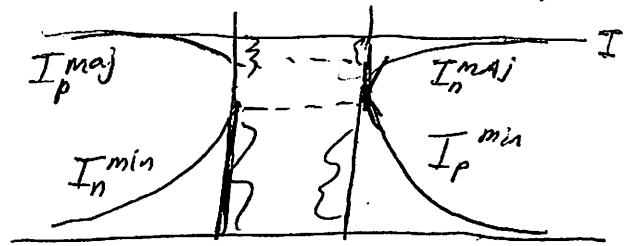
$$I_{tot} = qA \left(\frac{n_i^2}{N_A} \frac{L_n}{\tau_n} \left(\frac{D_n}{D_p} \right) + \frac{n_i^2}{N_D} \frac{L_p}{\tau_p} \left(\frac{D_p}{D_n} \right) \right) \left(e^{\frac{qV_F}{kT}} - 1 \right)$$

$$I_{tot} = qA \left(\frac{n_i^2}{N_A} \frac{D_n}{L_n} + \frac{n_i^2}{N_D} \frac{D_p}{L_p} \right) \left(e^{\frac{qV_F}{kT}} - 1 \right)$$

$$I_p^{min} = -qAD_p \frac{d}{dx_n} \phi_p(x_n)$$

$$I_n^{min} = qAD_n \frac{d}{dx_p} \phi_n(x_p)$$

$$I_n^{min}(x_p=0) + I_p^{min}(x_n=0) = I_{tot}$$

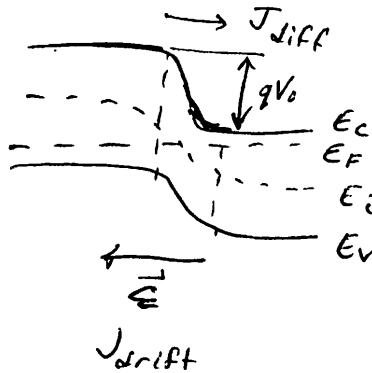
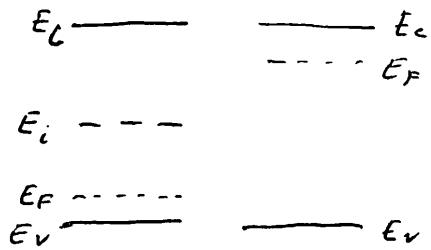


Average: 25.97 / 40

σ : 9.25

Regrades due Friday

ECE 340 HKN Review



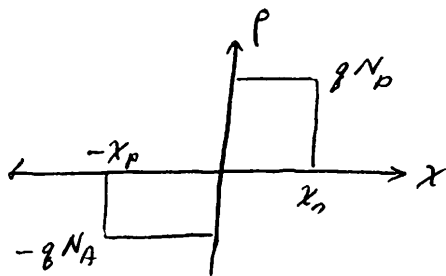
$$V_0 = F_p - F_n$$

$$\vec{J}_{diff,n} = \vec{J}_{drift,n}$$

$$q p \mu_p E = q p D_p \frac{dp}{dx} = 0$$

$$V_0 = \frac{kT}{q} \ln \left(\frac{N_A N_D}{n_i^2} \right)$$

$$\frac{p_p}{p_n} = e^{qV_0/kT}$$



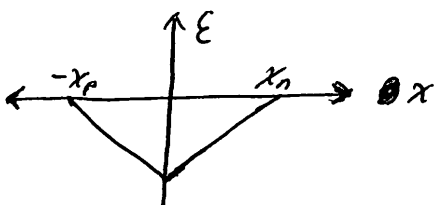
$$q N_A x_p = q N_D x_n$$

$$\vec{\nabla} \cdot \vec{E} = \frac{\rho}{\epsilon}$$

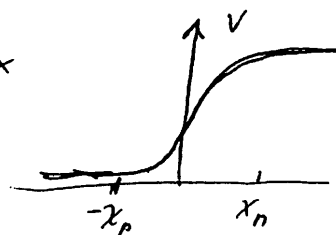
$$\frac{dE}{dx} = \frac{\rho}{\epsilon}$$

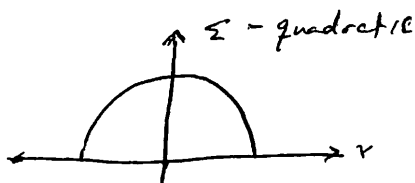
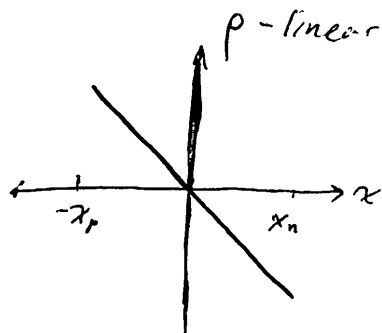
$$p\text{-region: } \frac{dE}{dx} = \frac{-qN_A}{\epsilon}$$

$$n\text{-region: } \frac{dE}{dx} = \frac{qN_D}{\epsilon}$$



$$\Delta V = - \int_{-x_p}^{x_n} \vec{E} dx$$

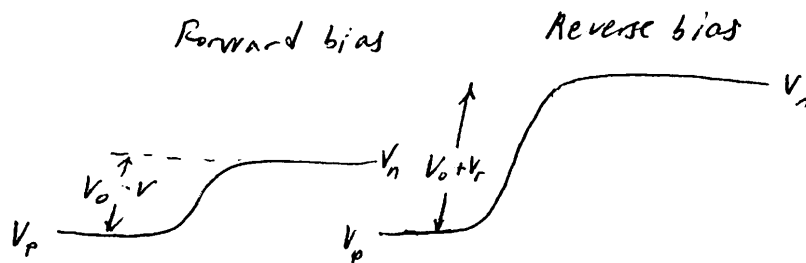
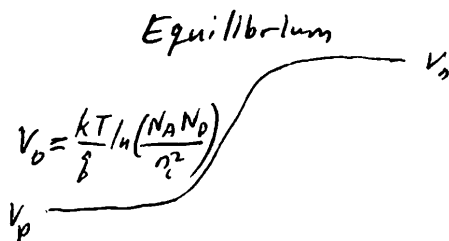




V - cubic

$$W = x_n + x_p$$

$$W = \left[\frac{2\epsilon V_0}{q} \left(\frac{1}{N_A} + \frac{1}{N_D} \right) \right]^{1/2}$$



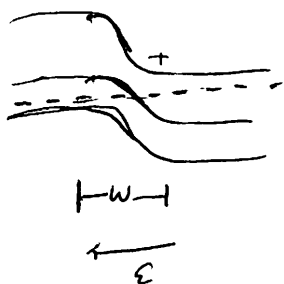
less diffusion current

~~but~~ drift current

insensitive to voltage

lower built-in field
depletion region shrinks
b/c less charge exposed
less bias introduced

higher built-in field



$$J_{th} \propto (W + L_p + L_n)$$

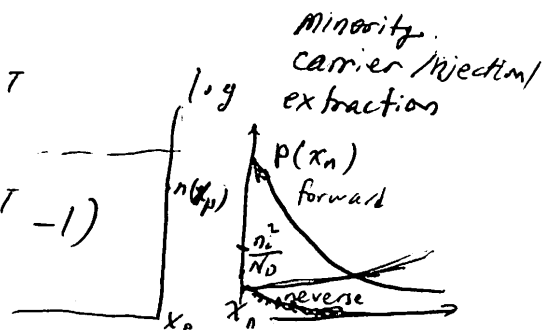
$$J = J_0 \left(\underbrace{e^{qV/kT}}_{\text{Diffusion}} - 1 \right) \underbrace{1}_{\text{Drift}}$$

$$\frac{p(-x_p)}{p(x_n)} = e^{q(V_0 - V)/kT}$$

$$\frac{p(x_n)}{p_n} = e^{qV/kT}$$

$$\Delta p = p (e^{qV/kT} - 1)$$

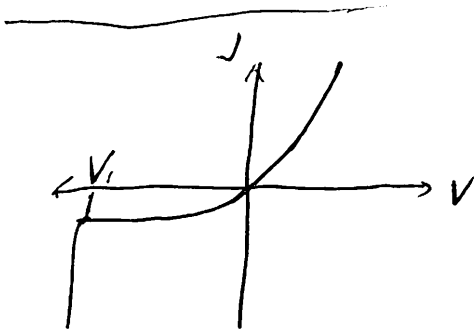
$$J_p = -q D_p \frac{d\Delta p}{dx}$$



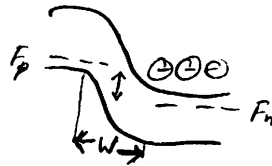
$$J = \left(q \frac{D_p}{L_p} p_n + q \frac{D_n}{L_n} n_p \right) \left(e^{q\Delta V/kT} - 1 \right)$$

$$\Delta p(x) = p_n \left(e^{qV/kT} - 1 \right) e^{-x/L_p}$$

$$\Delta n(x) = n_p \left(e^{qV/kT} - 1 \right) e^{-x/L_n}$$



Zener
- Tunneling



- high doping

$$W \propto \left(\frac{1}{N_A} + \frac{1}{N_D} \right)^{1/2}$$

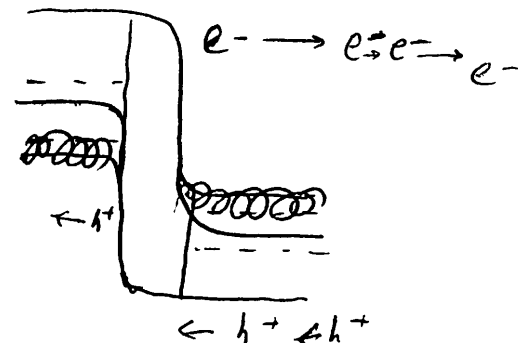


Tunneling current $\propto \frac{\Delta E}{kT}$

$T \uparrow$ easier to tunnel

Avalanche

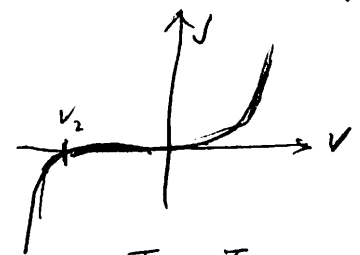
- carrier Multiplication



high magnitude Φ voltage

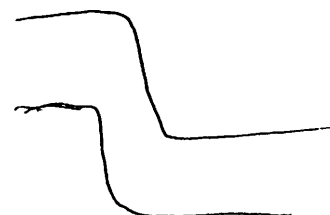
relatively Φ low doping

$$h\nu \gg 1.43 \text{ eV}$$



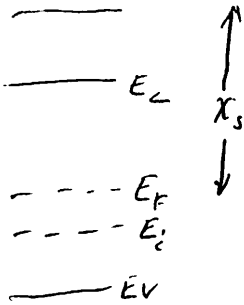
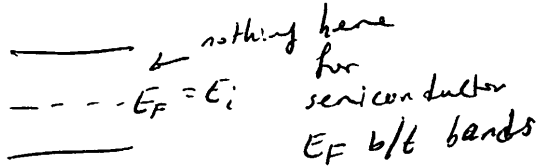
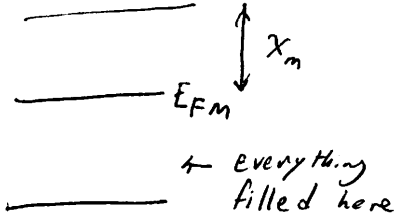
$$T_2 > T_1$$

$$|V_2| > |V_1|$$

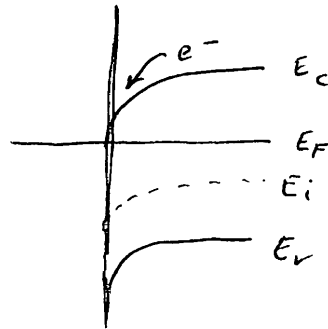


$$C \approx \frac{\epsilon A}{W}$$

$$W = \left[\frac{2\epsilon(V_0 - V)}{q} \frac{1}{N_D} \right]^{1/2} \quad p+n$$



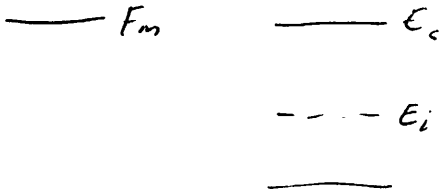
n type



ohmic contact

material more n-type
at junction than in bulk

$$n \propto \exp\left(\frac{E_c - E_F}{kT}\right)$$



Rectifying/shottky
ohmic

n-type

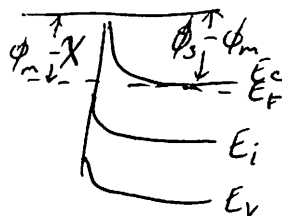
p-type

$$\phi_m > \phi_s$$

$$\phi_s > \phi_m$$

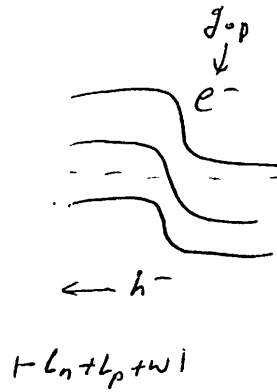
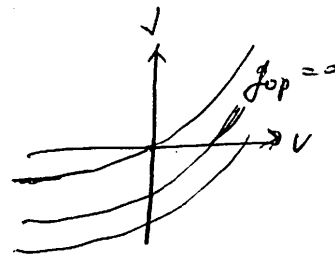
$$\phi_s > \phi_m$$

$$\phi_m > \phi_s$$

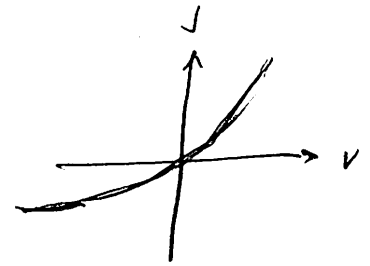


Optoelectronics

- photo diode
- solar cell
- LED/Laser

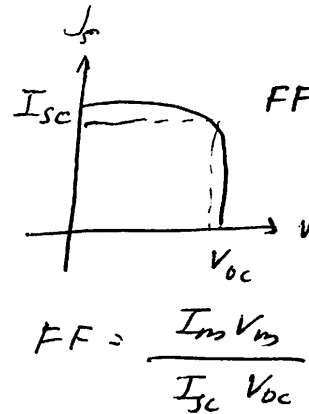
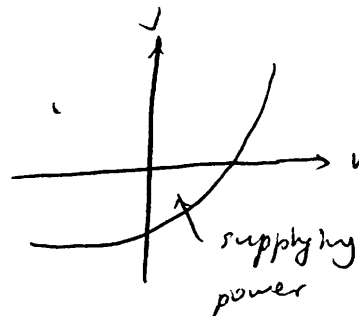
Si: $h\nu = 1.2 \text{ eV}$ 

$$J = J_{th} (e^{qV/kT} - 1) - J_{op}$$

GaAs $E_g \approx 1.43 \text{ eV}$ 

increase photon flux does nothing b/c photons not absorbed

solar cells



solar cell - want long carrier lifetimes

laser - ~~short~~ short carrier lifetimes / high recombination

LEDs - spontaneous, random polarization/orientation

laser - coherent, same orientations

lasers

 E_c

$$F_n - F_v > E_g$$

 E_v

Reverse bias - temperature dependence - Zener / Avalanche breakdown

$T \uparrow$ Zener tunneling require higher mag voltage to breakdown

Avalanche

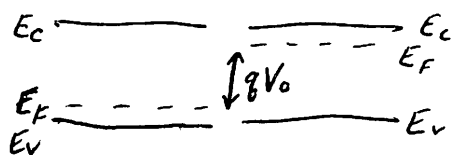
" lower " "

ECE 340 Monday 13 ~~Nov~~ Nov Lecture

Review for MT II.

Midterm - Ch. 5 & 8. No Ch. 6.

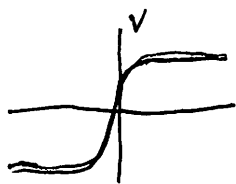
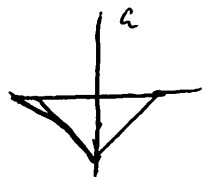
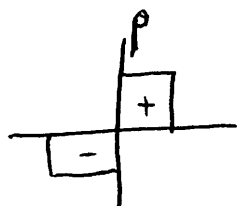
Form PN junction Built-in potential



Space charge

Assume only ionized donors in the depletion region

doping high \rightarrow shallow side
penetration



Key Eqns

Forward and reverse bias on pn junctions

Forward: smaller total elec field
ext + built in in diff directions

Reverse: ext + built in in same dir
larger total elec field

Current flow in pn junctions:

hole diffusion, hole drift, electron diffusion, electron drift

Equilibrium

Forward bias, minority carrier diffusion

$$\delta p(x_n) = \Delta p e^{-x_n/L_p}$$

Excess carrier distribution

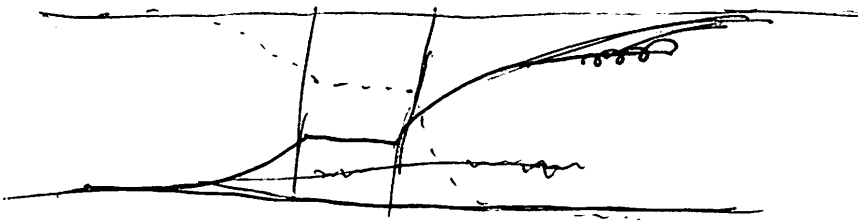
Diffusion current

Hole diffusion current

$$I_p(x_n) = -q A D_p \frac{d\delta p(x_n)}{dx_n} = q A \frac{D_p}{L_p} \delta p(x_n)$$

$$I_p(x_n=0) = q A \frac{D_p}{L_p} \Delta p_n = q A \frac{D_p}{L_p} p_n (e^{qV/kT} - 1)$$

Drift and diffusion in forward bias



Quasi-Fermi level at forward bias

$$n_n p_n e^{qV_f/kT} = n_i^2 e^{(qV_f/kT)} = n_i^2 e^{(F_n - F_p)/kT}$$

only at equilibrium $n_p = n_i^2$

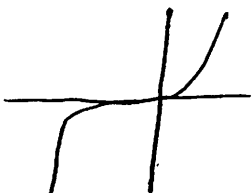
PN junction at reverse bias

Barrier larger

$$\Delta p = p_n [e^{q(-V_r)/kT} - 1] \approx -p_n$$

$$\Delta n \approx -n_p$$

Reverse Bias Breakdown



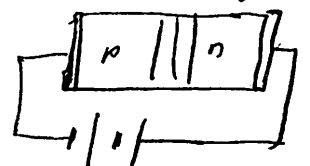
Zener Breakdown

- High doping
- occurs at low voltages

Avalanche Breakdown

- Low doping
- occurs at high voltages

pnud - through



penetration depth
= depletion length

pn junction capacitance

AC signal



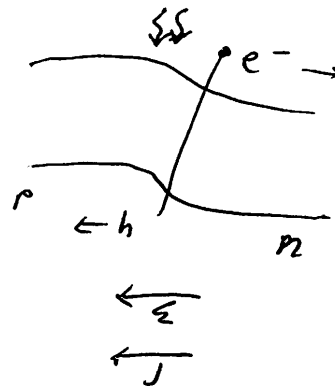
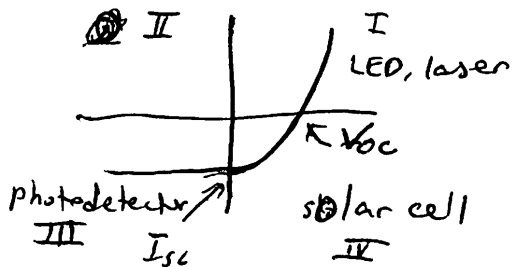
$$C_j = \frac{dQ}{dV} = A \sqrt{\frac{q\epsilon}{2(V_0 - V)}} \frac{N_d N_a}{N_a + N_d} = \boxed{\frac{\epsilon A}{W} = C_j}$$

junction capacitance
diffusion capacitance

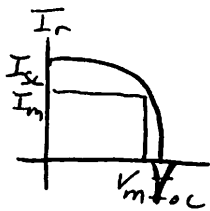
OPTOELECTRONICS

Current in an illuminated junction

$$I = I_{th} (e^{qV/kT} - 1) - I_{op}$$



Solar cell figure-of-merit



$$P_m = I_m V_m$$

Fill factor

$$FF = \frac{I_m V_m}{I_{oc} V_{oc}}$$

"how square"
the curve is

Efficiency

$$\eta$$

Photodiode figure of merit

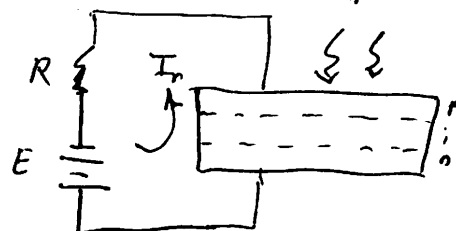
Internal quantum efficiency

$$\eta_{in} = \frac{I_{op}/q}{P_{abs}/h\nu}$$

External quantum efficiency

$$\eta_{ext} = \frac{I_{op}/q}{P_{in}/h\nu}$$

Efficiency high, large depletion width
Responsivity/frequency, sm dept. width



Light-emitting diode

$$h\nu_{out} =$$

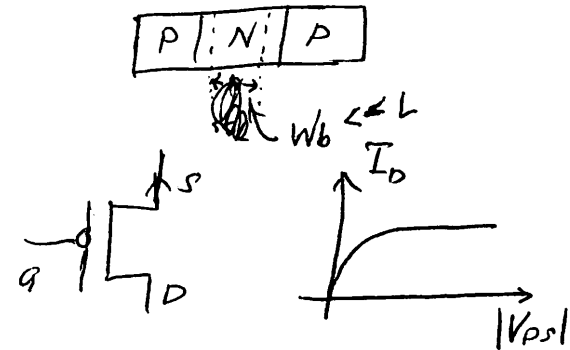
Laser

ECE 340 Wed 6 December Lecture

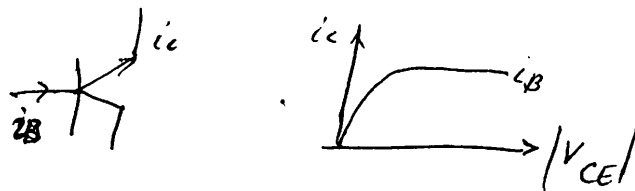
Prof. Kim

PNP BJT

! W is not depletion width of N region

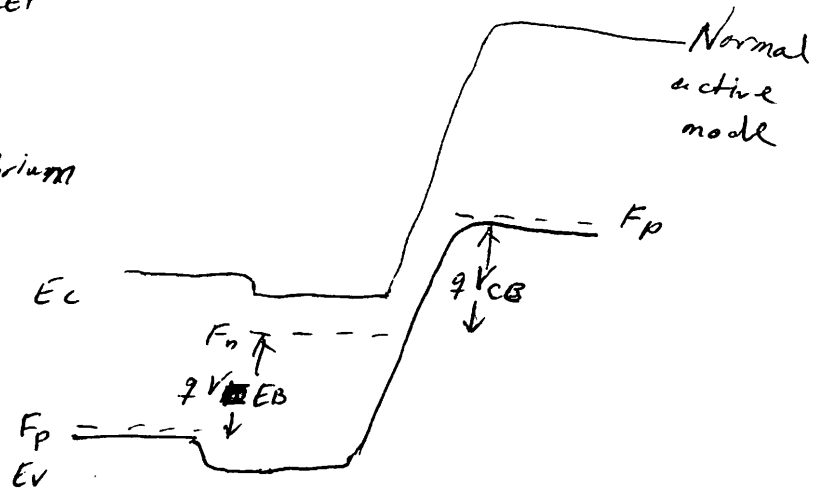
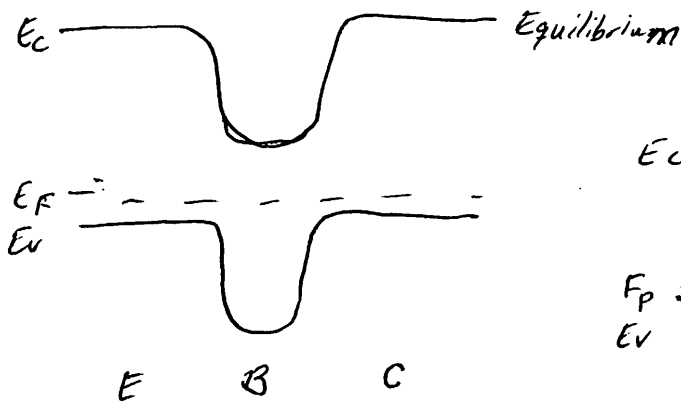


voltage controlled

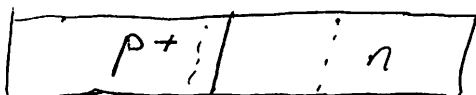


current controlled

Energy Band Diagram



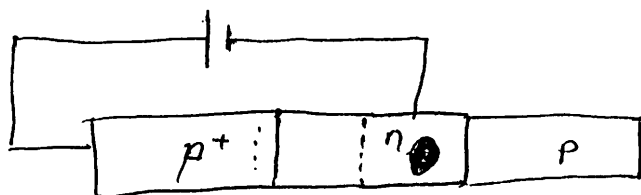
PNP BJT



$G-R=0$ at equilibrium

$R=0$ at reverse bias

$\hookrightarrow G$ only



$$I_C = I_{Cn} + I_{Cp}$$

$$\beta = \frac{I_{Cp}}{I_{Cn}}$$

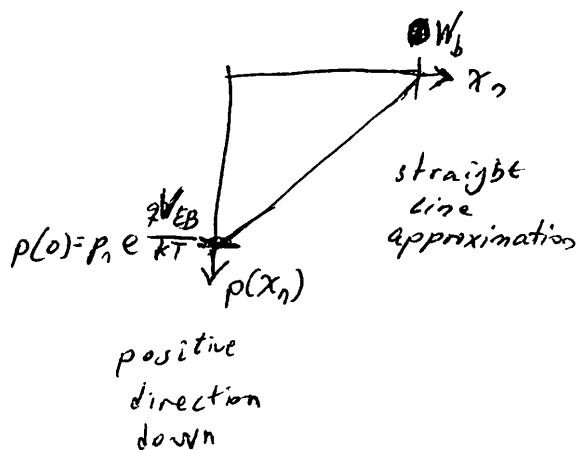
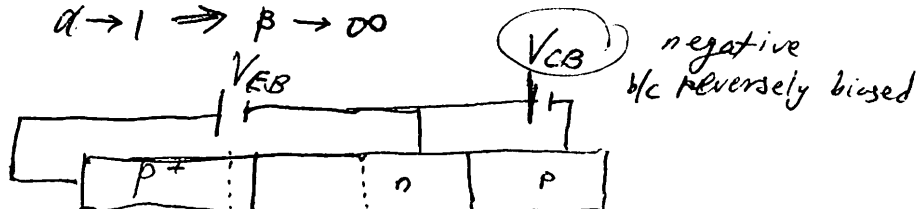
$$I_C = I_{Cp} = \beta I_{E} = \beta I_{Cn} = 2I_{Cn}$$

$$\beta = \frac{I_C}{I_B}$$

$$I_B = I_{E} - I_{Cn} = (1 - \alpha) I_E$$

$$\beta < 1$$

$$\alpha \rightarrow 1 \Rightarrow \beta \rightarrow \infty$$



$$\Delta p = p - p_n$$

Emitter Current

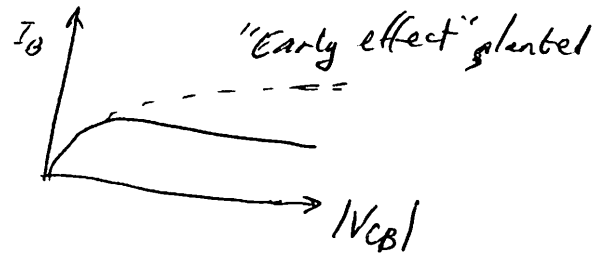
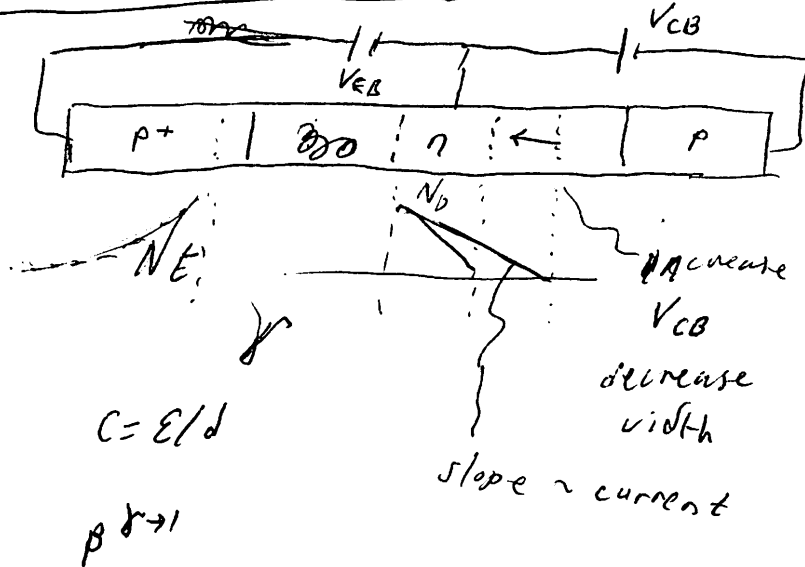
$$\frac{q^2}{NA}$$

Emitter Injection Efficiency:

$$\beta = \frac{1}{1 + \frac{\mu_n^E W_b N_D^B}{\mu_p^B L_n N_A^E}}$$

material properties - cannot change

punch thru



$$I_C = I_{C_n} + I_{C_p}$$

$$\gamma = \frac{I_{C_p}}{I_{C_n} + I_{C_p}}$$

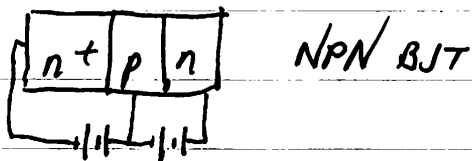
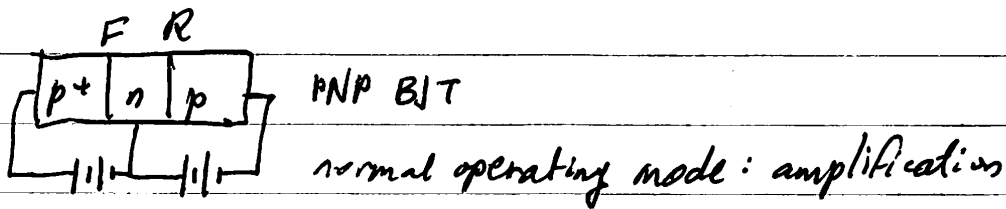
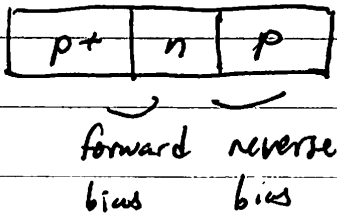
$$\beta \gamma = \frac{I_C}{I_B(N_{comb})} = \frac{\beta}{1-\beta} = \frac{\frac{qAD_p}{W_p} \Delta p_E}{\frac{qAW_b}{2\tau_p} \Delta p_E} = \frac{2L_p^2}{W_b^2}, \text{ for } W_b \ll L_p$$

Transit Time

$$\tau_t = \frac{W_b^2}{2D_p}$$

$$\tau_p = \frac{L_p^2}{D_p}$$

$$L_p = \sqrt{D_p \tau_p}$$



Collector current

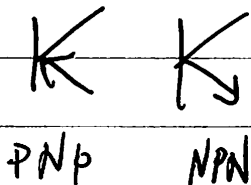
Base current

- recombination current - some amount supplied every & time
- injection current.

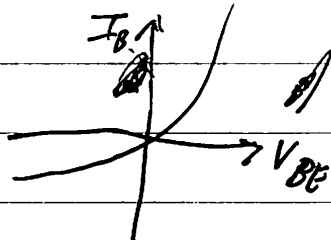
→ Current gain (for $\beta \approx 1$)

$$\beta \gamma^{-1} = \frac{I_c}{I_b(\text{recomb})} = \frac{2D_p \tau_p}{W_p^2}$$

Common-emitter amplifier and small signal current gain



$$I_B = qA \left(\frac{W_b}{2\tau_p} p_n + \frac{D_n}{L_n} n_p \right) (e^{eV_{BE}/kT} - 1)$$



What is the voltage that fall on the BJT?

What is the collector current?

Output characteristic

~ similar ~~to~~ to MOS FET.

$$G_{EB} = \frac{dI_B}{dV_{EB}} = \frac{1}{kT} I_B$$

$$I_B = \frac{V_{BB} - V_{BE}}{R}$$

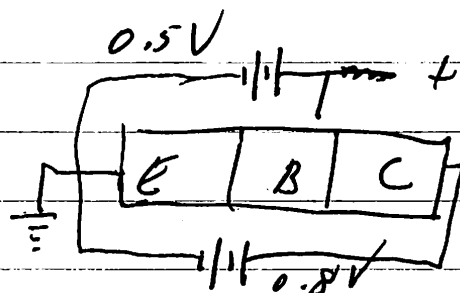
Voltage gain: $\frac{V_{out}}{V_{in}}$

Example

Emitter $N_D = 2 \times 10^{18} / \text{cm}^3$

Base $N_A = 2 \times 10^{17} / \text{cm}^3$

Collector $N_D = 6 \times 10^{16} / \text{cm}^3$



$$\beta = \frac{I_C}{I_B}$$

normal active region

cutoff

saturation

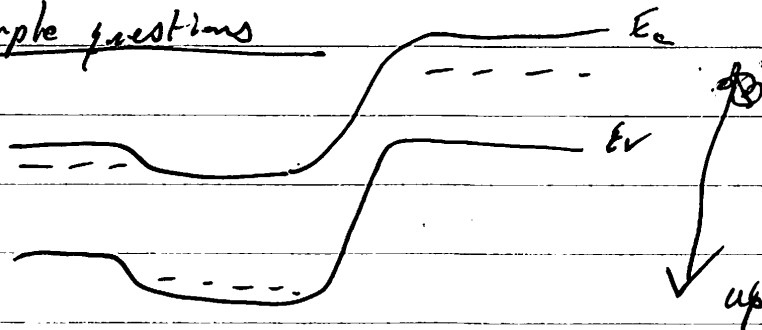
inverted

V_{BE} (forward bias)

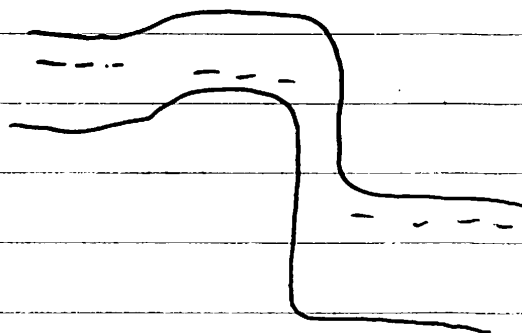
V_{BC} (forward bias)

Example questions

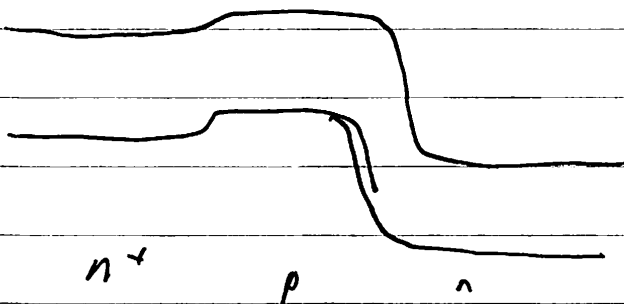
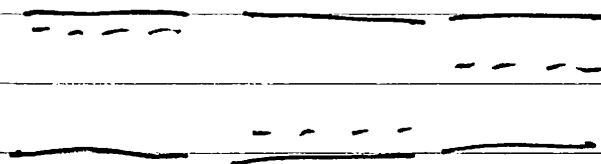
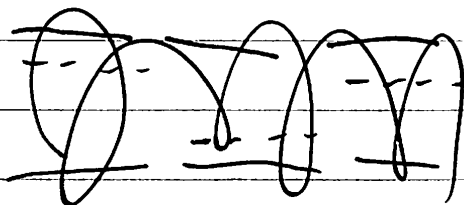
b)



ⓐ b)



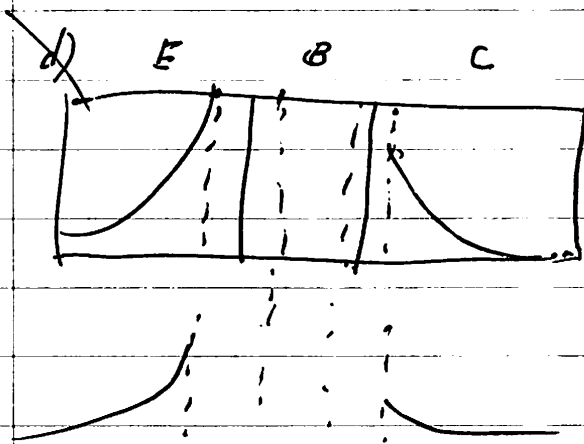
At equilibrium



c)

E	B	C
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ⓐ



Always np so for npn it is V_{BE}
 V_{BC}